

Notice of References Cited

Application/Control No.

09/892,210

Applicant(s)/Patent Under
Reexamination
SCHMIDT ET AL.

Examiner

Hae M Hyeon

Art Unit

2839

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,818,054	04-1989	George et al.	385/135
	B	US-6,021,909	02-2000	Tang et al.	211/183
	C	US-6,044,194	03-2000	Meyerhoefer, Carl E.	385/134
	D	US-6,102,214	08-2000	Mendoza, Jose-Filonel Tawag	211/26
	E	US-6,170,784	01-2001	MacDonald et al.	248/65
	F	US-6,338,413	01-2002	Walter et al.	211/26
	G	US-2002/0092127 A1	07-2002	Nhep, Ponharith	16/232
	H	US-D463,253 S	09-2002	Canty, Mark E.	D8/356
	I	US-2002/0149923 A1	10-2002	Witty et al.	361/828
	J	US-6,468,112	10-2002	Follingstad et al.	439/719
	K	US-6,489,565	12-2002	Krietzman et al.	174/101
	L	US-6,501,899	12-2002	Marrs et al.	385/135
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.